

**Search Notes**

Application/Control No.

10/710,799

Examiner

M. Lee

Applicant(s)/Patent under  
Reexamination

CHIN, YUAN-CHANG

Art Unit

2622

**SEARCHED**

Class	Subclass	Date	Examiner
348	468, 569, 716, 552, 553, 589	2/2/2007	ML
715	542, 535,		
	536, 716		
386	95, 96		
	98, 69		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	2/2/2007	ML